

<b>Notice of References Cited</b>	Application/Control No. 10/663,456		Applicant(s)/Patent Under Reexamination HEDIN ET AL.	
	Examiner Sean Sprigg		Art Unit 3712	Page 1 of 1

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*	C	US-2004/0002375	01-2004	Ogawa, Yoshio	463/20
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**NON-PATENT DOCUMENTS**

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